SLOVENSKI STANDARD

SIST EN 61674:1998/A1:2003

april 2003

Medical electrical equipment - Dosimeters with ionization chambers and/or semi-conductor detectors as used in X-ray diagnostic imaging

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ICS 11.040.50; 17.240

Referenčna številka
SIST EN 61674:1998/A1:2003(en)

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EUROPEAN STANDARD **EN 61674/A1**

NORME EUROPÉENNE

EUROPÄISCHE NORM September 2002

ICS 11.040.50

English version

Medical electrical equipment - Dosimeters with ionization chambers and/or semi-conductor detectors as used in X-ray diagnostic imaging

(IEC 61674:1997/A1:2002)

Appareils électromédicaux - Dosimètres à chambres d'ionisation et/ou à détecteurs à semi-conducteurs utilisés en imagerie de diagnostic à rayonnement X (CEI 61674:1997/A1:2002)

Medizinische elektrische Geräte - Diagnostikdosimeter mit Ionisationskammern und/oder Halbleiterdetektoren für den Einsatz an diagnostischen Röntgeneinrichtungen (IEC 61674:1997/A1:2002)

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This amendment A1 modifies the European Standard EN 61674:1997; it was approved by CENELEC on 2002-09-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This amendment exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Luxembourg, Malta, Netherlands, Norway, Portugal, Slovakia, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Ref. No. EN 61674:1997/A1:2002 E

Foreword

The text of document 62C/333/FDIS, future amendment 1 to IEC 61674, prepared by IEC SC 62C, Equipment for radiotherapy, nuclear medicine and radiation dosimetry, of IEC TC 62, Electrical equipment in medical practice, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as amendment A1 to EN 61674:1997 on 2002-09-01.

The following dates were fixed:

– latest date by which the amendment has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2003-06-01
– latest date by which the national standards conflicting with the amendment have to be withdrawn	(dow)	2005-09-01

Endorsement notice

The text of amendment 1:2002 to the International Standard IEC 61674:1997 was approved by CENELEC as an amendment to the European Standard without any modification.

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INTERNATIONAL STANDARD

IEC 61674

1997

AMENDMENT 1
2002-06

Amendment 1

Medical electrical equipment – Dosimeters with ionization chambers and/or semi-conductor detectors as used in X-ray diagnostic imaging

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Amendement 1

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Appareils électromédicaux – Dosimètres à chambres d'ionisation et/ou à détecteurs à semi-conducteurs utilisés en imagerie de diagnostic à rayonnement X

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Commission Electrotechnique Internationale
International Electrotechnical Commission
Международная Электротехническая Комиссия

PRICE CODE C

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FOREWORD

This amendment has been prepared by subcommittee SC 62C: Equipment for radiotherapy, nuclear medicine and radiation dosimetry, of IEC Technical Committee 62: Electrical equipment in medical practice.

The text of this amendment is based on the following documents:

FDIS	Report on voting
62C/333/FDIS	62C/339/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of the base publication and its amendments will remain unchanged until 2006. At this date, in accordance with the committee's decision, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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CONTENTS

Add, on page 5, after 6.8.3, the title of the new subclause 6.8.4, and renumber the existing 6.8.4 as 6.8.5:

6.8.4 Surges

6.8.5 Voltage dips, short interruptions and voltage variations

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Add the following new subclause 6.8.4:

6.8.4 Surges

The maximum spurious indications (both transient and permanent) of the display or data output due to surges shall be less than the limits given in table 7). The test is not to be performed on the connection lines between the detector and the measuring assembly.

For mains-operated instruments compliance shall be checked by observing and recording the indications of the display and any data output terminals while measurements are performed on the most sensitive range (if the ranges are selectable), both with and without the presence of disturbances induced by surges (IEC 61000-4-5). The severity level shall be level 3 as described in that standard.

NOTE Complete "latch-up" of the MEASURING ASSEMBLY which would not lead to an incorrect DOSE / DOSE RATE value being indicated is allowed.

Renumber the existing subclause 6.8.4 as 6.8.5 and replace the text, as follows:

6.8.5 Voltage dips, short interruptions and voltage variations

The maximum spurious indications (both transient and permanent) of the display or data output terminals due to voltage dips, short interruptions and voltage variations shall be less than the limits given in table 7.

For mains-operated instruments, compliance with this performance requirement shall be checked by observing and recording the indications of the display and any data output terminals while measurements are performed on the most sensitive range, both with and without the presence of conducted disturbances induced by voltage dips, short interruptions and voltage variations as described in IEC 61000-4-11. Test levels shall be 40 % U_T with duration of 25 periods for voltage dips and interruptions and 2 s/1 s/2 s for decreasing voltage/reduced voltage/increasing voltage in the case of voltage variations.

NOTE A complete "latch-up" of the MEASURING ASSEMBLY which would not lead to an incorrect AIR KERMA, AIR KERMA LENGTH or AIR KERMA RATE value being indicated is allowed.

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Table 7 – LIMITS OF VARIATION for the effects of INFLUENCE QUANTITITES

Amend the reference conditions for radiation quality, d) ATTENUATED BEAM to read as follows (modifications are underlined):

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INFLUENCE QUANTITY	MINIMUM RATED RANGE	REFERENCE CONDITIONS	LIMITS OF VARIATION *L*	Subclause
ATTENUATED BEAM [1]	100 – 150 kV W 12,5 – 47,5 mm Al	120 kV 42,5 mm Al (RQA 9 IEC 61267)	±5 %	6.1